## Notice of References Cited Application/Control No. 10/736,007 Examiner DuyVu n. Deo Applicant(s)/Patent Under Reexamination BEAUDRY ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-5,466,389	11-1995	llardi et al.	510/175
	В	US-6,468,362	10-2002	Chen et al.	134/26
	С	US-5,853,491	12-1998	Schulz, Peter	134/2
	D	US-2004/0029395	02-2004	Zhang et al.	438/748
	Е	US-2004/0029388	02-2004	Verhaverbeke et al.	438/689
	F	US-2003/0051742	03-2003	Boyers, David G.	134/30
	G	US-2004/0221877	11-2004	Bergman, Eric J.	134/034
	н	US-	0		
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	*				
	0					
	Р					
	ø					
	ĸ					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	·				
	>					
	>					
	x					

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.